Application/Control No.	Applicant(s)/Patent under Reexamination	
10/603,300	TAM ET AL.	
Examiner	Art Unit	
Hwei-Siu C. Payer	3724	

Hwei-Siu C. Payer

SEARCHED					
Class	Subclass	Date	Examiner		
030	393	updated on 1/18/06	Pager		
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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